

E_T^{miss} bin (GeV)	Di-EM p_T reweighting	Jet multiplicity reweighting	Shape difference between ee and ff	Statistical uncertainty of ee sample
$100 \leq E_T^{\text{miss}} < 110$	15%	34%	18%	31%
$110 \leq E_T^{\text{miss}} < 120$	17%	15%	12%	33%
$120 \leq E_T^{\text{miss}} < 140$	33%	29%	14%	42%
$E_T^{\text{miss}} \geq 140$	39%	20%	150%	71%